

<b>Notice of References Cited</b>	Application/Control No. 10/707,456	Applicant(s)/Patent Under Reexamination SU ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0025708 A1	02-2003	Irie et al.	345/589
	B	US-6,741,031	05-2004	Harada et al.	313/582
	C	US-6,498,593	12-2002	Fujimoto et al.	345/60
	D	US-6,373,195	04-2002	Whang et al.	315/169.3
	E	US-5,967,872	10-1999	Betsui et al.	445/24
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
	Q					
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	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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